

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
30-5000-(4015)-Div3SERIAL NO.
09/783,835LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Shozo Nagano et al.FILING DATE
February 14, 2001GROUP
Unknown 1742

U.S. PATENT DOCUMENTS

Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
B	AA	3,963,934	06/15/76	Ormrod	250	499	
B	AB	4,132,614	01/02/79	Cuomo et al.	204	192 EC	
B	AC	4,149,907	04/17/79	Wronski et al.	148	1.5	
B	AD	4,159,909	07/03/79	Wilson	75	170	
B	AE	4,198,283	04/15/80	Class et al.	204	298	
B	AF	4,209,375	06/24/80	Gates et al.	204	192 R	
B	AG	4,395,979	05/31/83	Pierce et al.	204	298	
B	AH	4,545,882	10/08/85	McKelvey	204	192 R	
B	AI	4,629,859	12/16/96	Reddy	219	121 LM	
B	AJ	4,814,053	03/21/89	Shimokawato	204	192.15	
B	AK	5,171,411	12/15/92	Hillendahl et al.	204	192.12	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
B	AL	EP 0 882 813 A1	09.12.98	Europe (Takahashi)				
B	AM	61084389 A2	28.04.86	Japan (Takewaki) - Abstract only				
B	AN	61113740 A2	31.05.86	Japan (Tanaka) - Abstract only				
B	AO	62127438	09.06.87	Japan (Tatsuta) - Abstract only				
B	AP	63033174	12.02.88	Japan (Kazuka) - Abstract only				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

B	AR		Dierckxsens et al., <i>Effect of trace elements on the recrystallization behavior of high purity oxygen-containing copper</i> , ERZMETAL 28(11), 496-500 (1975). Abstract only.
B	AS		Lucke et al., <i>Physical Metallurgy Principles</i> , 5 ACTA MET. 298 (1957).
B	AT	x	Pierson et al., <i>Total sputtering yield of Ag/Cu alloys for low energy argon ions</i> , NUCL. INSTR. AND METH. IN PHYS. RES. 108 B, pp. 290-299 (1996). Full text of article submitted in abstract earlier.

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AB	AA	5,215,639	06/01/93	Boys	204	192.12	
	AB	5,242,566	09/07/93	Parker	204	298.2	
	AC	5,268,236	12/07/93	Dumont et al.	428	636	
	AD	5,282,943	02/01/94	Lannutti et al.	204	192.12	
	AE	5,282,946	02/01/94	Kinoshita et al.	204	298.13	
	AF	5,336,386	08/09/94	Marx et al.	204	298.12	
	AG	5,397,050	03/14/95	Mueller	228	193	
	AH	5,490,914	02/13/96	Hurwitt et al.	204	289.12	
	AI	5,589,040	12/31/96	Nishimura	204	192.26	
	AJ	5,674,367	10/07/97	Hunt et al.	204	298.12	
	AK	5,693,203	12/02/97	Ohhashi et al.	240	298.12	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL	63064211	22.03.88	Japan (Furukawa) - Abstract only				
	AM	63118033	23.05.88	Japan (Sumitomo Metal mining Co.) - Abstract only				
	AN	63235442 A2	30.09.88	Japan (Furukawa) - Abstract only				
	AO	1-96374	14.04.89	Japan				X
	AP	1-96376	14.04.89	Japan (Ishikura)			X	

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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<i>2</i>	AA	5,772,858	06/30/98	Tepman	204	192.12	
	AB	5,833,823	11/10/98	Gruenenfelder et al.	204	298.09	
	AC	5,846,389	12/08/98	Levine et al.	204	192.1	
	AD	6,010,583	01/04/00	Annavarapu et al.	148	513	
	AE	6,028,003	02/22/00	Frisa et al.	438	653	
	AF	6,039,855	03/21/00	Wollenberg	204	298.12	
	AG	6,042,752	03/28/00	Mitsui	252	520.1	
	AH	6,068,742	05/30/00	Daxinger et al.	204	298.09	
	AI	6,086,735	07/11/00	Gilman et al.	204	298.12	
	AJ	6,117,281	09/12/00	Novbakhtian	204	192.16	
	AK	6,121,685	09/19/00	Gardner	257	762	
<i>2</i>	AL	6,139,701	10/31/00	Pavate et al.	204	192.17	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>2</i>	AM	02301585	13.12.90	Japan (Furukawa) - Abstract only				
<i>2</i>	AN	05078195 A2	30.03.93	Japan (Sugiura) - Abstract only				
<i>2</i>	AO	10-287939	27.10.98	Japan (Eguchi)			X	
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA 09/556,488		Kardokus et al. (as filed)			04/21/2000
	AB 09/615,474		Kardokus et al. (as filed and as amended)			07/13/2000
	AG 09/714,714		Kardokus (as filed)			11/15/2000
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

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						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

2	AR	U.S. patent application Ser. No. 09/556,488, Kardokus et al., filed April 21, 2000
	AS	U.S. patent application Ser. No. 09/615,474, Kardokus et al., July 13, 2000
2	AT	U.S. patent application Ser. No. 09/714,714, Kardokus et al., November 13, 2000

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E	AA	4,189,084	02-1980	Johnson et al.			
	AB	09/556,488		J. Kardokus (Amendment dated 7-10-01)			04-21-2000
	AC	09/714,714		J. Kardokus (Amendment dated 5-22-02)			11-15-2000
	AD						
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	AJ						
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
E	AL	8510400	01-1986	China (abstract)	1	1		
E	AM	62036798	08-1987	Japan (abstract)	1	1		
E	AN	61227972	10-1986	Japan (abstract)	1	1		
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

E	AR		Reda et al., "Amorphous copper-silver films with high stability", Int. Cent. Theor. Phys., Trieste, Italy, 1983. (Abstract only) The year is sufficiently early so that the month is not in issue.
E	AS		U.S. patent application Ser. No. 09/556,488, filed 4/21/00
E	AT		U.S. patent application Ser. No. 09/714,714, filed 11/15/00

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